

AMENDMENTS TO THE CLAIMS

The following listing of claims replaces all prior versions, and listings, of claims in the captioned patent application:

Listing of Claims:

1. (Previously Presented) A testing apparatus for concurrently testing components of a medical device, the testing apparatus comprising:

a plurality of testing stations configured to receive and communicably couple to a first component being of a first type and a second component being of a second type, wherein the first component is not of the second type and the second component is not of the first type ; and

at least one testing circuit communicably coupled to said plurality of testing stations and configured to concurrently apply a test to each of said first and second components and to measure a response of each of said first and second components to said test.

2. (Previously Presented) The testing apparatus of claim 1, wherein the medical device is a cochlear implant system and further wherein said first and second components comprise a cable and a transmitter coil of said cochlear implant system.

3-4. (Cancelled)

5. (Previously Presented) The testing apparatus of claim 1 wherein the plurality of testing stations comprise two or more stations configured to receive two or more types of cables and further configured to make an electrical connection to said cables.

6. (Cancelled)

7. (Previously Presented) The testing apparatus of claim 5 wherein each cable testing station for each of said two or more types of cables comprises a socket having a shape that is adapted to receive one of said two or more types of cables.
8. (Previously Presented) The testing apparatus of claim 1, wherein said plurality of testing stations comprise a coil testing station configured to test said transmitter coil.
9. (Previously Presented) The testing apparatus of claim 8 wherein the coil testing station comprises a planar area in the first surface on which transmitter coil can be placed during testing.
10. (Previously Presented) The testing apparatus of claim 9 wherein the planar area has an indicator provided thereon that provides an indication of where said transmitter coil should be placed during testing.
11. (Previously Presented) The testing apparatus of claim 10 wherein said indicator comprises a pictorial representation of said transmitter coil.
12. (Cancelled)
13. (Previously Presented) The testing apparatus of claim 1 wherein a first magnet is positioned at or below the planar surface, said first magnet adapted to provide magnetic alignment with a second magnet disposed adjacent said transmitter coil to maintain the coil in a correct position for testing.
14. (Previously Presented) The testing apparatus of claim 9 wherein said plurality of testing stations further comprises one or more coil testing stations configured to test a cable extending from the transmission coil.

15. (Previously Presented) The testing apparatus of claim 9 wherein the apparatus is configured to sense the specific type of components among said two or more types of components under test and further configured to access from the memory component the appropriate stored data for each said specific type of components .

16. (Previously Presented) The testing apparatus of claim 1, further comprising a control circuit configured to control the operations of the testing apparatus.

17. (Previously Presented) The testing apparatus of claim 16 wherein the control circuit comprises a microcontroller.

18. (Previously Presented) The testing apparatus of claim 17 wherein the control circuit comprises a memory component for the testing apparatus.

19. (Previously Presented) The testing apparatus of claim 17 wherein the microcontroller further comprises a microprocessor having an analog to digital converter (ADC) configured to digitize the measurements representative of the tested component.

20. (Previously Presented) The testing apparatus of claim 17 wherein the measurements from said at least one testing circuit is in the form of current and voltage levels, and further wherein said data indicating a desired response to said first test are in the form of voltage and current ranges associated with non-faulty cables and transmitter coils used in cochlear implant systems.

21. (Previously Presented) The testing apparatus of claim 1, further comprising an output component for outputting a result of said comparison.

22. (Previously Presented) The testing apparatus of claim 21 wherein said output component comprise a light configured to illuminate if the tested component passes the test.

23. (Previously Presented) The testing apparatus of claim 22, wherein said light is a light emitting diode (LED).

24. (Previously Presented) A method of concurrently testing components of a medical device using a testing apparatus having a plurality of testing stations, comprising:

receiving, by the testing apparatus, a first component being of a first type and a second component being of a second type, wherein the first component is not of the second type and the second component is not of the first type;

communicably coupling the first and second components with a first and second of said plurality of testing stations, respectively, of the testing apparatus; and

performing a test on said first and second components concurrently.

25. (Previously Presented) The method of testing of claim 24, wherein said performing a test comprises:

applying a first and second test to the first and second components;

measuring a response to each said applied first and second test;

retrieving stored data comprising desired response data for each said first and second test;
and

comparing the measured response to the desired response for each said first and second test.

26. (Previously Presented) The method of testing of claim 24, wherein the testing apparatus and at least one of the two components each have corresponding magnets, and further wherein said receiving at least two of said two or more types of components further comprises:

magnetically coupling at least one of said two components to the testing apparatus.

27. (Previously Presented) The method of testing of claim 25, further comprising:

sensing the specific type among the two or more types of components,

wherein said retrieved data corresponds to the sensed type of component from a plurality of stored data for each of the two or more types of components.

28. (Previously Presented) The testing apparatus of claim 1, further comprising a memory component configured to store data indicating a desired response to said first test.

29. (Previously Presented) The testing apparatus of claim 1, further comprising a comparator circuit configured to compare said measured response to a desired response stored in a memory component and to generate output indicating whether said measured response is at least substantially similar to said desired response.